

Single Pulse Avalanche Energy

Thermal Resistance, Junction to Case

Thermal Resistance, Junction to Ambient

Operating and Storage Junction Temperature Range

Power Dissipation

Power Dissipation

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS5672	FDMS5672	Power 56	13"	12mm	3000 units

T_C = 25°C

T_A = 25°C

Thermal Characteristics

E_{AS}

IP_D

T_J, T_{STG}

 $R_{\theta JC}$

mJ

\٨/

°C

°C/W

337

78

2.5

-55 to +150

1.6

50

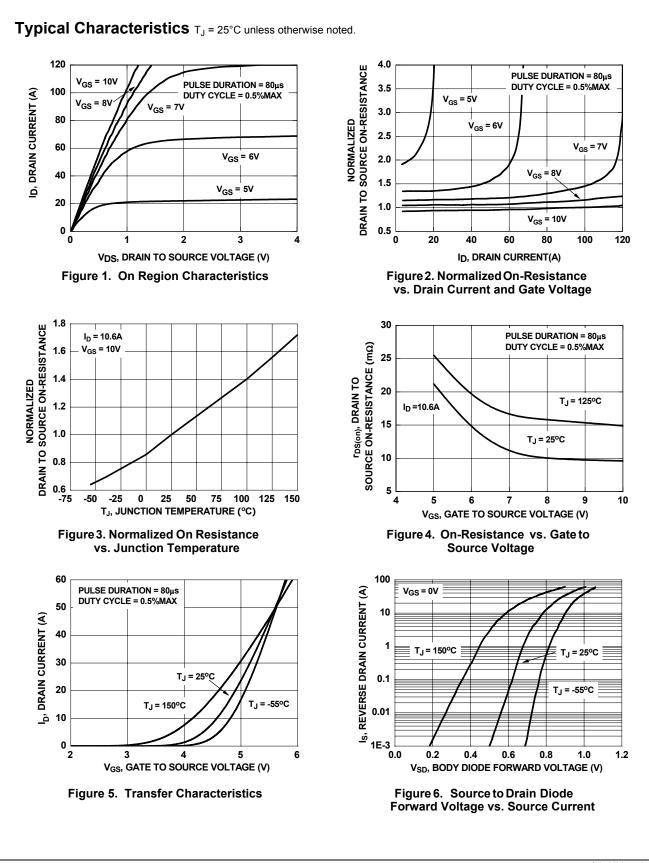
(Note 3)

(Note 1a)

(Note 1a)

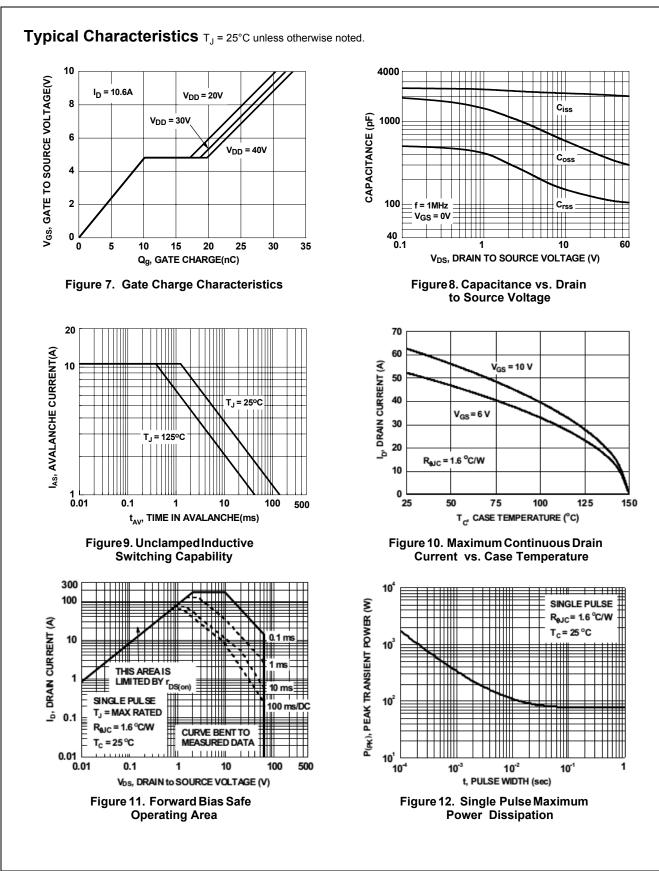
	Test Conditions	Min.	Тур.	Max.	Units	
cteristics						
Drain to Source Breakdown Voltage	I _D = 250μA, V _{GS} = 0V	60			V	
Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25°C		59		mV/°C	
Zero Gate Voltage Drain Current	V _{DS} = 48V, V _{GS} = 0V			1	μA	
Gate to Source Leakage Current	V_{GS} = ±20V, V_{DS} = 0V			±100	nA	
cteristics						
	$V_{CS} = V_{DS}$. In = 250µA	2	3.2	4	V	
		_	-			
Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25°C		-11		mV/°C	
	V _{GS} = 10V, I _D = 10.6A		9.4	11.5	_	
Drain to Source On Resistance	$V_{GS} = 6V, I_D = 8A$		13.0	16.5	mΩ	
	$T_J = 125^{\circ}C$		15.0	18.0		
Forward Transconductance	V _{DS} = 10V, I _D = 10.6A		26		S	
Characteristics						
			2100	2800	pF	
	$V_{DS} = 30V, V_{GS} = 0V,$ f = 1MHz				pF	
				180	pF	
Gate Resistance	f = 1MHz		1.2		Ω	
Characteristics					1	
			16	29	ns	
Rise Time	Vpp = 30V. lp = 10.6A		17	31	ns	
Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 6\Omega$		22	35	ns	
Fall Time			8	16	ns	
Total Gate Charge at 10V	$V_{GS} = 0V$ to 10V		32	45	nC	
Gate to Source Gate Charge	$v_{DD} = 30V$		10		nC	
Gate to Drain "Miller" Charge	ID - 10.0A		8.3		nC	
rce Diode Characteristics						
	$V_{CC} = 0V_{LC} = 10.6A$ (Note 2)		0.80	1.20	V	
-					ns	
Reverse Recovery Charge	— I _F = 10.6A, di/dt = 100A/μs		42	63	nC	
	Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current Cteristics Gate to Source Threshold Voltage Gate to Source Threshold Voltage Temperature Coefficient Drain to Source On Resistance Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance Characteristics Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Total Gate Charge at 10V Gate to Source Gate Charge Gate to Drain "Miller" Charge rce Diode Characteristics Source to Drain Diode Forward Voltage Reverse Recovery Time	CoefficientID 250μ A, referenced to 25° CZero Gate Voltage Drain Current $V_{DS} = 48V, V_{GS} = 0V$ Gate to Source Leakage Current $V_{GS} = \pm 20V, V_{DS} = 0V$ CteristicsGate to Source Threshold Voltage $I_D = 250\mu$ A, referenced to 25° CGate to Source Threshold Voltage $I_D = 250\mu$ A, referenced to 25° CTemperature Coefficient $I_D = 250\mu$ A, referenced to 25° CDrain to Source On Resistance $V_{GS} = 10V, I_D = 10.6A$ Drain to Source On Resistance $V_{GS} = 10V, I_D = 10.6A$, $T_J = 125^{\circ}$ CForward Transconductance $V_{DS} = 10V, I_D = 10.6A$ CharacteristicsInput CapacitanceInput Capacitance $V_{DS} = 30V, V_{GS} = 0V, f = 10.6A$ Output Capacitance $f = 1MHz$ Characteristicsf = 10.6ATurn-On Delay Time $F = 10.6A$ Rise Time $V_{DD} = 30V, I_D = 10.6A$ Turn-Off Delay Time $V_{GS} = 0V to 10V$ Fall Time $V_{GS} = 0V to 10V$ Gate to Source Gate Charge $I_D = 10.6A$ Gate to Drain "Miller" Charge $V_{GS} = 0V, I_S = 10.6A$ (Note 2)Reverse Recovery Time $I_C = 10.6A$ di/dt = 100A/us	CoefficientID 250μ A, referenced to 25° CZero Gate Voltage Drain Current $V_{DS} = 48V, V_{GS} = 0V$ Gate to Source Leakage Current $V_{GS} = \pm 20V, V_{DS} = 0V$ CteristicsGate to Source Threshold Voltage $V_{GS} = V_{DS}, I_D = 250\mu$ A2Gate to Source Threshold Voltage $I_D = 250\mu$ A, referenced to 25° CTemperature Coefficient $V_{GS} = 10V, I_D = 10.6A$ 2Drain to Source On Resistance $V_{GS} = 10V, I_D = 10.6A$ 2Forward Transconductance $V_{DS} = 10V, I_D = 10.6A$ 2CharacteristicsInput Capacitance $V_{DS} = 30V, V_{GS} = 0V, f = 10.6A$ 2CharacteristicsInput Capacitance $f = 1MHz$ 2CharacteristicsInput Capacitance $f = 100K, R_{GEN} = 6\Omega, f = 100K, R_{GEN} = 6\Omega$ 2Turn-On Delay Time $V_{GS} = 0V, I_D = 10.6A$ 22Fail Time $V_{GS} = 0V to 10V, R_{GEN} = 6\Omega$ 22Fail Time $V_{GS} = 0V to 10V, R_{DD} = 30V, I_D = 10.6A$ 2Total Gate Charge at 10V $V_{GS} = 0V to 10V, R_{DD} = 30V, I_D = 10.6A$ 2Gate to Source Gate Charge $V_{GS} = 0V to 10V, R_{DD} = 30V, I_D = 10.6A$ 2Gate to Drain "Miller" Charge $V_{GS} = 0V, I_S = 10.6A, (Note 2), Reverse Recovery Time1Le = 10.6A, di/dt = 100A/us111$	CoefficientID250µA, referenced to 25°C59Zero Gate Voltage Drain Current $V_{DS} = 48V, V_{GS} = 0V$ 6Gate to Source Leakage Current $V_{GS} = \pm 20V, V_{DS} = 0V$ 2Cateristics10 $V_{GS} = \pm 20V, V_{DS} = 0V$ 2Gate to Source Threshold Voltage $V_{GS} = \pm 20V, V_{DS} = 0V$ 2Temperature Coefficient $I_D = 250\muA$, referenced to 25°C-11Drain to Source On Resistance $V_{GS} = 10V, I_D = 10.6A$ 9.4 $V_{GS} = 10V, I_D = 10.6A, I_J = 125°C15.0Forward TransconductanceV_{DS} = 10V, I_D = 10.6A, I_J = 125°C15.0Forward TransconductanceV_{DS} = 10V, I_D = 10.6A, I_J = 10.6A, I_J = 10.6A, I_J = 10.6A26Characteristics1200375Input CapacitanceV_{DS} = 30V, V_{CS} = 0V, I_J = 10.6A, I_$	$\begin{array}{c c c c c c c c c c c c c c c c c c c $	

Pulse Test: Pulse Width < 300μs, Duty cycle < 2.0%.
Starting T_J = 25°C, L = 3mH, I_{AS} = 15A, V_{DD} = 60V, V_{GS} = 10V.
Pulsed Id please refer to Fig 11 SOA graph for more details.
Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

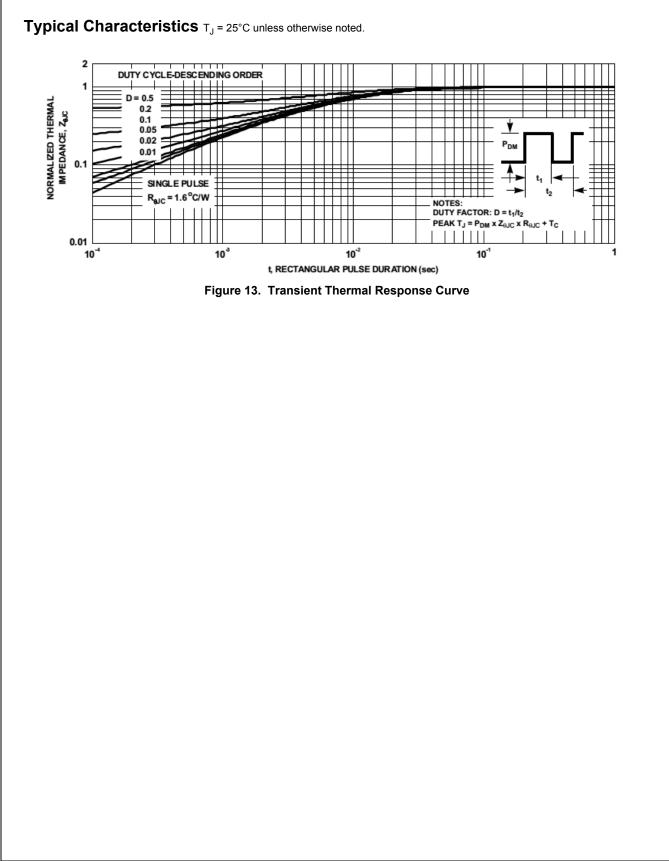


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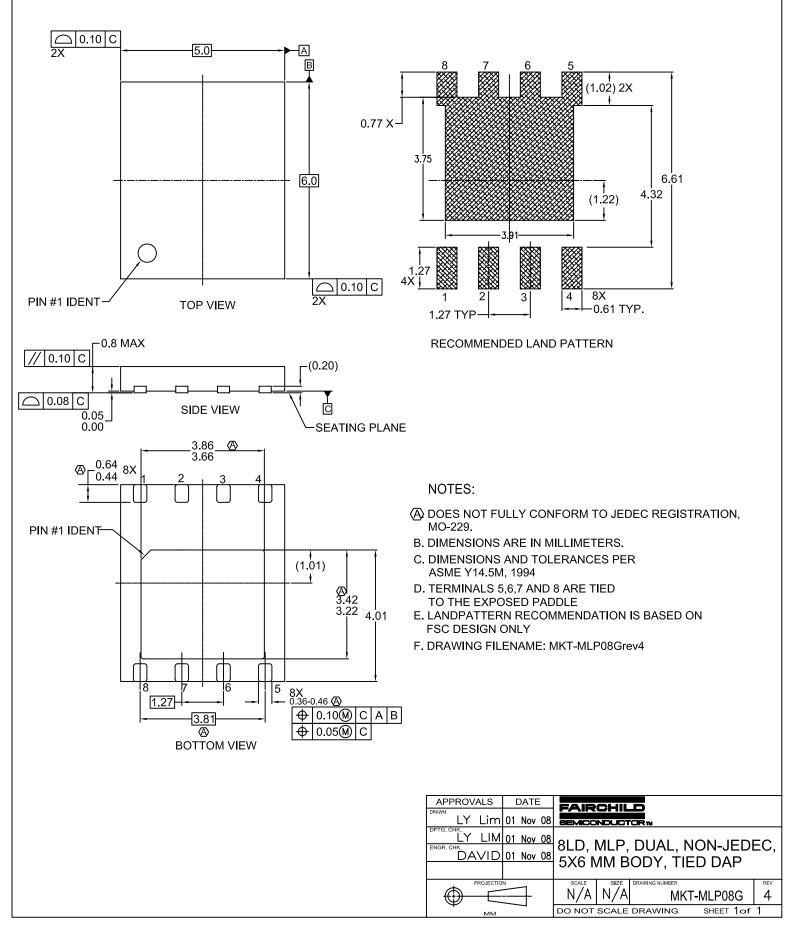


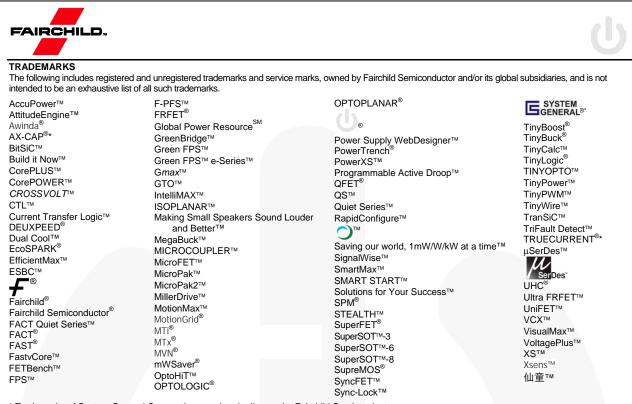
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FDMS5672 N-Channel UltraFET Trench[®] MOSFET

	REVISIONS		
NBR	DESCRIPTION	DATE	NAME/SITE
1	RELEASE TO DOCUMENT CONTROL	090305	David/FSPM
2	REVISE TO CORRECT DAP SIZE	080605	David/FSPM
3	I) REVISE TO CORRECT PKG THK		
	II) REVISE THE PKG PROFILE TOLERANCE	210306	CK/FSPM
4	ADD IN LEAD LENGTH FOR LAND PATTERN	220908	LY/FSPM





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